In the Claims:

Please amend claims 3, 5, 7 16, 17, 19, 21, 31 and 32. Please cancel claims 14, 33-36

The claims are as follows:

1. (Canceled)

2. (Previously Presented) The computer system of claim 31, wherein said simulated external memory mapped test device and said simulated switch are distributed among a plurality of simulated external memory mapped test device modules, each module of said plurality of simulated external memory mapped test device modules containing a portion of said simulated switch and connected to a respective second external I/O driver model of said second external I/O driver models.

3. (Currently Amended) The computer system of claim 31, wherein said simulated external memory mapped test device further includes a simulated address register.

4. (Canceled)

5. (Currently Amended) The computer system of claim 2, wherein each said simulated external memory mapped test device module further includes a simulated address register.

6. (Canceled)

7. (Currently Amended) The <u>computer</u> system of claim 31, wherein said simulated external

memory mapped test device and said simulated switch are distributed among a plurality of

simulated external memory mapped test device modules, each module of said plurality of

simulated external memory mapped test device modules containing a portion of said simulated

switch and connected to a respective <u>second external</u> I/O driver model of said one or more

<u>second external</u> I/O driver models<u>;</u> and

~~further including the method steps of~~ <u>executing said instructions causes the computer to</u>

<u>perform the further following steps</u>:

        loading code representing an additional simulated external memory mapped test

device module into said memory unit;

        said loading of said test case connecting one or more additional <u>second external</u>

I/O driver models to said additional simulated external memory mapped test device by

additional simulated I/O buses; and

        said loading of said test case connecting each additional <u>second external</u> I/O

driver model to a respective additional simulated I/O core by said simulated system bus,

each additional simulated I/O core comprising said model of integrated circuit design.

8-15 (Canceled)

16. (Currently Amended) The ~~computer~~ program ~~storage device~~ <u>product</u> of claim 32, ~~said~~

~~method steps further including: distributing~~ <u>wherein</u> said simulated external memory mapped test

device and said simulated switch <u>are distributed</u> among a plurality of simulated external memory

mapped test device modules, each module of said plurality of simulated external memory

modules containing a portion of said simulated switch and connected to one of said simulated

I/O driver models.

17. (Currently Amended) The ~~computer~~ program ~~storage device~~ product of claim 32, ~~said~~

~~method steps further including: providing~~ wherein said simulated external memory mapped test

device ~~with~~ includes a simulated address register; and

    executing said instructions, further causes said computer to connect ~~setting~~ said simulated

switch ~~and controlling control said simulated~~ to one second external I/O driver model of said one

or more second external I/O driver models using address information programmed into said

simulated address register.

18. (Canceled)

19. (Currently Amended) The ~~computer~~ program ~~storage device~~ product of claim 16, ~~said~~

~~method steps further including: providing~~ wherein each simulated external memory mapped test

device ~~with~~ includes a corresponding simulated address register; and

    executing said instructions, further causes said computer to connect ~~setting~~ each portion

of said simulated switch ~~and controlling control each simulated~~ to one second external I/O driver

model of said one or more I/O driver models using address information programmed into its

corresponding ~~said~~ simulated address register.

20. (Canceled)

21. (Currently amended) The computer system of claim 31, wherein said one or more simulated I/O cores ~~includes~~ are each independently selected from the group consisting of a simulated 1394 I/O core, a simulated universal asynchronous receiver transmitter core, a simulated serial core[[s]], a simulated general purpose I/O core, and a direct memory access core ~~or combinations thereof~~.

22 -30 (Canceled)

31. (Currently Amended) A computer system comprising a processor and a computer-readable memory unit coupled to communicate with said processor, said memory unit containing instructions that when executed by the processor ~~implement a method for verifying an integrated circuit design, said method comprising the computer implemented steps of~~ causes the computer to perform the following steps:

loading code representing said integrated circuit design into said memory unit, said integrated circuit design including simulated I/O cores, a simulated ~~external~~ memory controller, a simulated I/O controller, a simulated bus system and a simulated processor, said simulated I/O cores and said simulated I/O controller connected to said simulated processor by said simulated system bus;

loading into said memory unit, code representing (i) an external memory model[[,]] connected to a simulated external memory mapped test device and to said simulated memory controller, (ii) one or more first external I/O driver models ~~into said memory unit~~ connected between said simulated I/O cores and said simulated external memory mapped test device and (iii) one or more second external I/O driver models connected between a simulated switch of said

simulated external memory mapped test device and said I/O controller, said ~~simulated external~~

~~memory mapped test device including~~ a simulated switch programmably connectable to said one

or more second external I/O driver models in response to computer-executable instructions in a

test case, ~~to said simulated I/O controller and to said external memory model, said I/O driver~~

~~models connected to corresponding said simulated I/O cores by~~, all said connections of (i), (ii)

and (iii) by corresponding simulated I/O buses;

loading [[a]] said test case , said test case comprising [[a]] said list of computer-

executable instructions [[on]] for said simulated processor into said external memory model, said

instructions describing selection of one or more simulated I/O cores and corresponding second

external I/O models, allocation of pins of said I/O controller to selected simulated I/O cores and

switch positions of said simulated switch to connect said corresponding second external I/O

models to said I/O controller[[,]];

~~said loading of~~ executing said test case and allocating and connecting I/O pins of said

simulated I/O controller to one or more of said simulated I/O cores, and connecting said

simulated external memory mapped test device to said simulated I/O controller through said

corresponding second external I/O models ~~and to said one or more of said simulated I/O cores;~~

executing test stimuli of said test case on said simulated processor in order to generate

data representing a response of said computer simulation model of said integrated circuit design

to said test case; and

outputting said data representing a response of said computer simulation model of said

integrated circuit design to said test case to another computer readable media or another

computer, (ii) display said data representing a response of said computer simulation model of

said integrated circuit design on a computer screen, or both (i) and (ii).

32. (Previously presented) A <u>computer</u> program ~~storage device readable by machine, tangibly embodying a program of instructions executable by machine to perform method steps a method for verifying an integrated circuit design, said method steps comprising~~ <u>product embodied on a computer readable medium comprising code that, when executed, causes a computer to perform the following</u>:

~~generating~~ <u>load</u> a model of said integrated circuit design <u>into a memory of said computer,</u> said integrated circuit design including simulated I/O cores <u>including a simulated general purpose core,</u> a simulated external memory controller, a simulated I/O controller, a simulated bus system and a simulated processor, said simulated I/O cores and said simulated I/O controller connected to said simulated processor by said simulated system bus;

~~loading~~ <u>load into said memory unit,</u> code representing <u>(i)</u> an external memory model[[,]] <u>connected to</u> a simulated external memory mapped test device and <u>to said simulated memory controller, (ii)</u> one or more <u>first external</u> I/O driver models ~~into said memory unit~~ <u>connected between said simulated I/O cores and said simulated external memory mapped test device and (iii) one or more second external I/O driver models connected between a simulated switch of said simulated external memory mapped test device and said I/O controller,</u> said ~~simulated external memory mapped test device including a~~ simulated switch programmably connectable to said one or more <u>second external</u> I/O driver models <u>in response to computer-executable instructions in a test case,</u> ~~to said simulated I/O controller and to said external memory model, said I/O driver models connected to corresponding said simulated I/O cores by,~~ <u>all said connections of (i), (ii) and (iii)</u> by corresponding simulated I/O buses;

~~loading a~~ load said test case, said test case comprising [[a]] said list of computer-executable instructions [[on]] for said simulated processor into said external memory model, said instructions describing selection of one or more simulated I/O cores and corresponding second external I/O models, allocation of pins of said I/O controller to selected simulated I/O cores and switch positions of said simulated switch to connect said corresponding second external I/O models to said I/O controller[[,]];

~~said loading of~~ executing said test case and allocating and connecting I/O pins of said simulated I/O controller to one or more of said simulated I/O cores, and connecting said simulated external memory mapped test device to said simulated I/O controller through said corresponding second external I/O models ~~and to said one or more of said simulated I/O cores~~;

~~and~~

execute ~~executing~~ test stimuli of said test case on said simulated processor;

~~in order to~~ generate data representing a response of said computer simulation model of said integrated circuit design to said test case; and

(i) output said data representing a response of said computer simulation model of said integrated circuit design to said test case to another computer readable media or another computer, (ii) display said data representing a response of said computer simulation model of said integrated circuit design on a computer screen, or both (i) and (ii).

33-36 (Canceled)